

Notice of References Cited	Application/Control No. 10/774,594		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Mark A. X Radtke		Art Unit 2165	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,864,502 A	09-1989	Kucera et al.	704/8
*	B	US-6,353,896 B1	03-2002	Holzmann et al.	714/38
*	C	US-2003/0154444 A1	08-2003	Tozawa et al.	715/513
*	D	US-2004/0073870 A1	04-2004	Fuh et al.	715/513
*	E	US-2005/0060645 A1	03-2005	Raghavachari et al.	715/513
*	F	US-6,966,027 B1	11-2005	Krasinski, Raymond J.	715/513
*	G	US-7,055,093 B2	05-2006	Tozawa et al.	715/513
*	H	US-7,165,216 B2	01-2007	Chidlovskii et al.	715/513
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B Bouchou, D Duarte, MHF Alves, D Laurent. "Extending tree automata to model XML validation under element and attribute constraints" Pages 184-190. Document modified 23 March 2003. Accessed 16 November 2007. Available online.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.